



MATRA M H S

T-46-23-05

Preliminary

September 1990

DATA SHEET

HM 65687

64 k x 1 ULTIMATE CMOS SRAM

FEATURES

- ACCESS TIME
MILITARY/INDUSTRIAL : 45/55 ns (max)
COMMERCIAL : 35/45 ns (max)
- VERY LOW POWER CONSUMPTION
ACTIVE : 175.0 mW (typ)
STANDBY : 2.0 μ W (typ)
DATA RETENTION : 0.8 μ W (typ)
- WIDE TEMPERATURE RANGE :
- 55 TO + 125°C
- 300 MILS WIDTH PACKAGE
- TTL COMPATIBLE INPUTS AND OUTPUTS
- ASYNCHRONOUS
- SINGLE 5 VOLT SUPPLY
- EQUAL CYCLE AND ACCESS TIME
- GATED INPUTS : NO PULL-UP/DOWN
RESISTORS ARE REQUIRED

DESCRIPTION

The HM 65687 is a very low power CMOS static RAM organized as 65536 x 1 bit. It is manufactured using the MHS high performance CMOS technology named super CMOS.

With this process, MHS is the first to bring the solution for applications where fast computing and low consumption are mandatory, such as the aerospace electronics, the portable instruments or PC's.

Utilising an array of six transistors (6T) memory cells,

the HM 65687 combines an extremely low standby supply current (typical value = 0.1 μ A) with a fast access time at 35 ns over the full temperature range. The high stability of the 6T cell provides excellent protection against soft errors due to noise.

Extra protection against heavy ions is given by the use of an epitaxial layer of a P substrate.

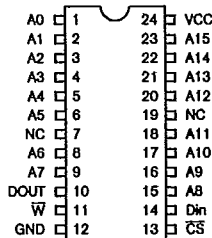
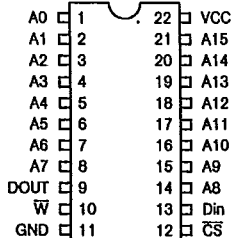
The HM 65687 is processed following the test methods of MIL STD 883C.

PACKAGES

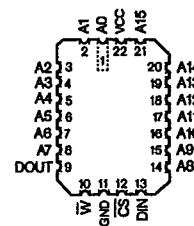
Plastic 300 mils, 22 pins, DIL.
Ceramic 300 mils, 22 pins, DIL.

SOIC & SOJ* 300 mils, 24 pins
LCC, 22 pins.

Pinout DIL 22/24 pins (top view)



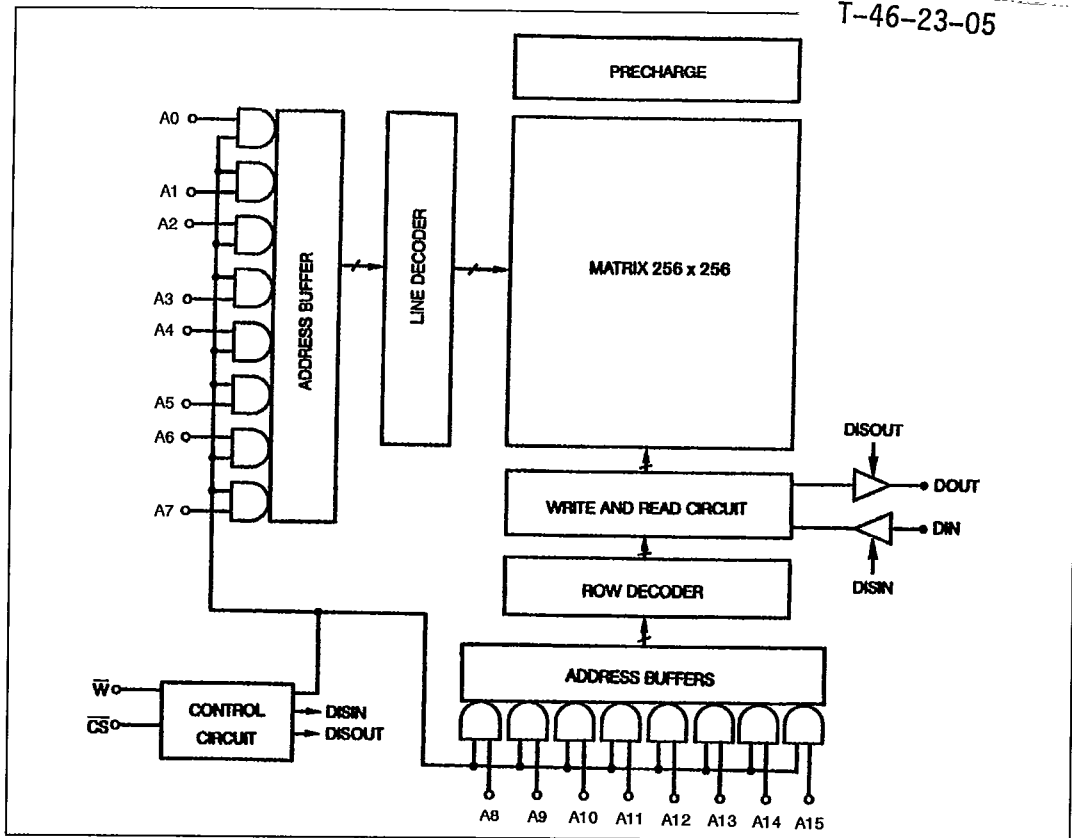
Pinout LCC 22 pins (top view)



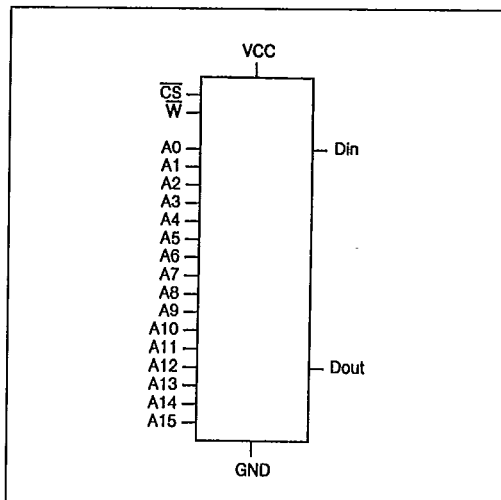
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BLOCK DIAGRAM

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LOGIC SYMBOL



PIN NAMES

A0-A15 : Address inputs	$\overline{W}$: Write enable
Din : Input	V_{CC} : Power
Dout : Output	GND : Ground
$\overline{CS}$: Chip select	

TRUTH TABLE

$\overline{CS}$	$\overline{W}$	DATA-IN	DATA-OUT	MODE
H	X	Z	Z	Deselect
L	H	Z	Valid	Read
L	L	Valid	Z	Write

L = low, H = high, X = H or L, Z = High impedance

ABSOLUTE MAXIMUM RATINGS

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Supply voltage to GND potential : -0.3 V to $+7.0\text{ V}$ Input or Output voltage applied : (Gnd -0.3 V) to ($V_{CC} + 0.3\text{ V}$)Storage temperature : -65°C to $+150^{\circ}\text{C}$ **OPERATING RANGE**

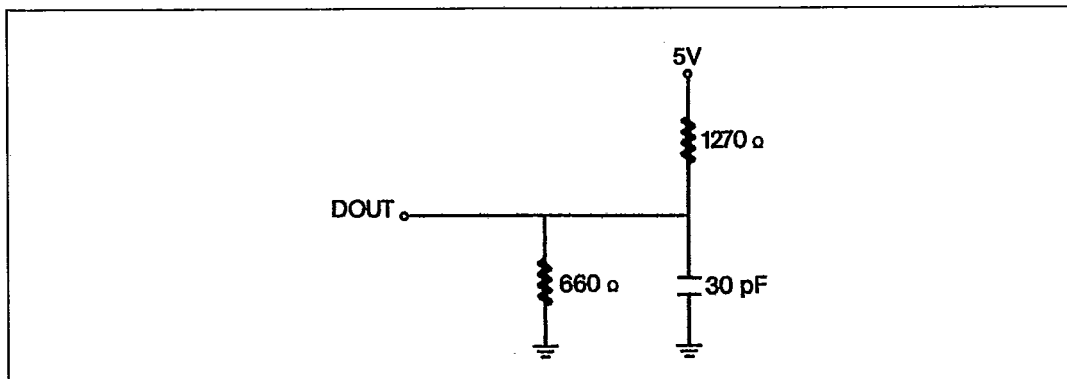
		OPERATING VOLTAGE	OPERATING TEMPERATURE
Military	(-2)	$V_{CC} \pm 10\%$	-55°C to $+125^{\circ}\text{C}$
Industrial	(-9)	$V_{CC} \pm 10\%$	-40°C to $+85^{\circ}\text{C}$
Commercial	(-5)	$V_{CC} \pm 10\%$	0°C to $+70^{\circ}\text{C}$

RECOMMENDED DC OPERATING CONDITIONS

PARAMETER	DESCRIPTION	MINIMUM	TYPICAL	MAXIMUM	UNIT
V_{CC}	Supply Voltage	4.5	5.0	5.5	V
Gnd	Ground	0.0	0.0	0.0	V
V_{IL} (1)	Input Low Voltage	-0.3	0.0	0.8	V
V_{IH}	Input High Voltage	2.2	—	$V_{CC} + 0.3\text{ V}$	V

Note : 1. V_{IL} min = -0.3 V or -1.0 V pulse width 50 ns.**CAPACITANCE**

PARAMETER	DESCRIPTION	MINIMUM	TYPICAL	MAXIMUM	UNIT
C_{in} (2)	Input capacitance	—	—	5	pF
C_{out} (2)	Output capacitance	—	—	7	pF

Note : 2. $T_A = 25^{\circ}\text{C}$, $f = 1\text{ MHz}$, $V_{CC} = 5.0\text{ V}$, these parameters are not 100 % tested.**OUTPUT LOAD**

ELECTRICAL CHARACTERISTICS DC PARAMETER

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PARAMETER	DESCRIPTION	MINIMUM	TYPICAL	MAXIMUM	UNIT
IIX (3)	Input leakage current	- 1.0	-	1.0	μ A
IOZ (3)	Output leakage current	- 1.0	-	1.0	μ A
VOL (4)	Output low voltage	-	-	0.4	V
VOH (4)	Output high voltage	2.4	-	-	V

Notes : 3. $Gnd < V_{in} < V_{cc}$, $Gnd < V_{out} < V_{cc}$ output disabled.4. $V_{cc} \min$, $I_{OL} = 4.0 \text{ mA}$, $I_{OH} = -1.0 \text{ mA}$.

Consumption for Commercial specification (- 5) :

SYMBOL	PARAMETER	65687 B-5	65687 S-5	65687 -5	65687 C-5	UNIT	VALUE
ICCSB (5)	Standby supply current	10	15	10	15	mA	max
ICCSB1 (6)	Standby supply current	1.0	75	1.0	75	μ A	max
ICC (7)	Operating supply current	10	15	10	15	mA	max
ICCOP (8)	Operating supply current	65	75	65	75	mA	max

Consumption for Industrial specification (- 9) :

SYMBOL	PARAMETER	65687 B-9	65687 S-9	65687 -9	65687 C-9	UNIT	VALUE
ICCSB (5)	Standby supply current	15	20	15	20	mA	max
ICCSB1 (6)	Standby supply current	5.0	100.0	5.0	100.0	μ A	max
ICC (7)	Operating supply current	15	20	15	20	mA	max
ICCOP (8)	Operating supply current	75	100	75	100	mA	max

Consumption for Military specification (- 2) :

SYMBOL	PARAMETER	65687 B-2	65687 S-2	65687 -2	65687 C-2	UNIT	VALUE
ICCSB (5)	Standby supply current	15	20	15	20	mA	max
ICCSB1 (6)	Standby supply current	50.0	500.0	50.0	500.0	μ A	max
ICC (7)	Operating supply current	15	20	15	20	mA	max
ICCOP (8)	Operating supply current	75	100	75	100	mA	max

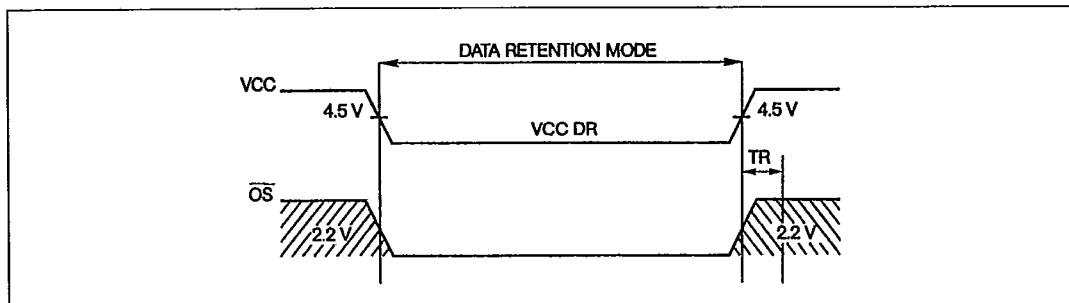
Notes : 5. $\overline{CS} \geq V_{IH}$.6. $\overline{CS} \geq V_{cc} - 0.3 \text{ V}$, $I_{out} = 0 \text{ mA}$.7. $\overline{CS} \leq V_{IL}$, $I_{out} = 0 \text{ mA}$, $V_{in} = Gnd/V_{cc}$.8. $V_{cc} \max$, $I_{out} = 0 \text{ mA}$, $f = \max$, $V_{in} = Gnd/V_{cc}$.

DATA RETENTION MODE

MHS CMOS RAMs are designed with battery backup applications in mind. Data retention voltage and supply current are guaranteed over temperature. The following rules insure data retention :

1. Chip select ($\overline{CS}$) must be held high during data retention ; within V_{CC} to $V_{CC} + 0.3$ V

2. $\overline{CS}$ must be kept between $V_{CC} + 0.3$ V and 70 % of V_{CC} during the power up and power down transitions
3. The RAM can begin operation > 35 ns after V_{CC} reaches the minimum operating voltage (4.5 V).

TIMING**DATA RETENTION CHARACTERISTICS**

PARAMETER	DESCRIPTION	MINIMUM	TYPICAL (9)	MAXIMUM	UNIT
VCCDR	V _{CC} for data retention	2.0	—	—	V
TCDR	Chip deselected to data retention time	0.0	—	—	ns
TR	Operation recovery time	TAVAV (10)	—	—	ns
ICCDR1 (11)	Data retention current @ 2.0 V : HM-65687 (B)-5	—	0.1	0.5	μA
	HM-65687 (B)-9	—	0.1	2.0	μA
	HM-65687 (B)-2	—	0.1	20.0	μA
	HM-65687S/C-5	—	0.1	30.0	μA
	HM-65687S/C-9	—	0.1	30.0	μA
	HM-65687S/C-2	—	0.1	200.0	μA
ICCDR2 (11)	Data retention current @ 3.0 V : HM-65687 (B)-5	—	0.3	1.0	μA
	HM-65687 (B)-9	—	0.3	3.0	μA
	HM-65687 (B)-2	—	0.3	30.0	μA
	HM-65687S/C-5	—	0.3	50.0	μA
	HM-65687S/C-9	—	0.3	50.0	μA
	HM-65687S/C-2	—	0.3	300.0	μA

Notes : 9. TA = 25°C.

10. TAVAV = Read cycle time.

11. $\overline{CS} = V_{CC}$, $V_{in} = Gnd/V_{CC}$, this parameter is only tested to $V_{CC} = 2$ V.

ELECTRICAL CHARACTERISTICS AC PARAMETERS

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AC CONDITIONS :

Input pulse levels : Gnd to 3.0 V
 Input rise : 5 ns

Input timing reference levels : 1.5 V
 Output load : 1 TTL gate + 30 pF

WRITE CYCLE : Commercial specification

SYMBOL	PARAMETER	65687 B-5	65687 S-5	65687 -5	65687 C-5	UNIT	VALUE
TAVAV	Write cycle time	35	35	45	45	ns	min
TAVWL	Address set-up time	0	0	0	0	ns	min
TAVWH	Address valid to end of write	35	35	45	45	ns	min
TDVWH	Data set-up time	20	20	25	25	ns	min
TELWH	CS low to write end	35	35	45	45	ns	min
TWLQZ (12)	Write low to high Z	15	15	20	20	ns	max
TWLWH	Write pulse width	30	30	40	40	ns	min
TWHAX	Address hold to end of write	5	5	5	5	ns	min
TWHDX	Data hold time	3	3	3	3	ns	min
TWHQX (12)	Write high to low Z	0	0	0	0	ns	min

WRITE CYCLE : Industrial and military specification

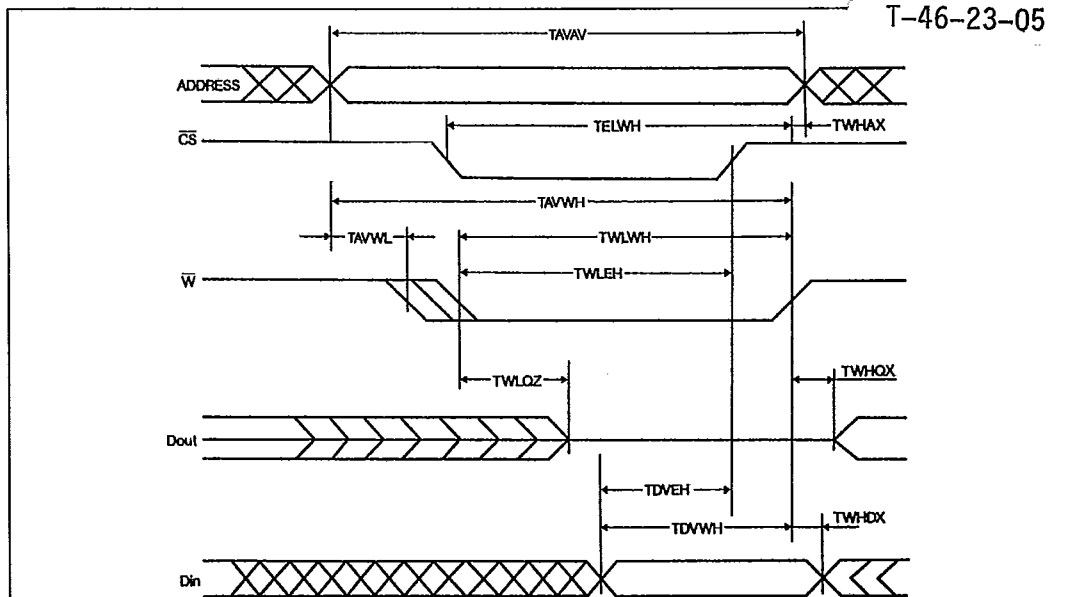
SYMBOL	PARAMETER	65687 B-9/2	65687 S-9/2	65687 -9/2	65687 C-9/2	UNIT	VALUE
TAVAV	Write cycle time	45	45	55	55	ns	min
TAVWL	Address set-up time	0	0	0	0	ns	min
TAVWH	Address valid to end of write	45	45	55	55	ns	min
TDVWH	Data set-up time	20	20	25	25	ns	min
TELWH	CS low to write end	45	45	55	55	ns	min
TWLQZ (12)	Write low to high Z	15	15	20	20	ns	max
TWLWH	Write pulse width	40	40	50	50	ns	min
TWHAX	Address hold to end of write	5	5	5	5	ns	min
TWHDX	Data hold time	3	3	3	3	ns	min
TWHQX (12)	Write high to low Z	0	0	0	0	ns	min

Note : 12. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

WRITE CYCLE

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Note : The internal write time of the memory is defined by the overlap of CS LOW and W LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input setup and hold timing should be referenced to the rising edge of the signal that terminates the write.

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READ CYCLE : Commercial specification

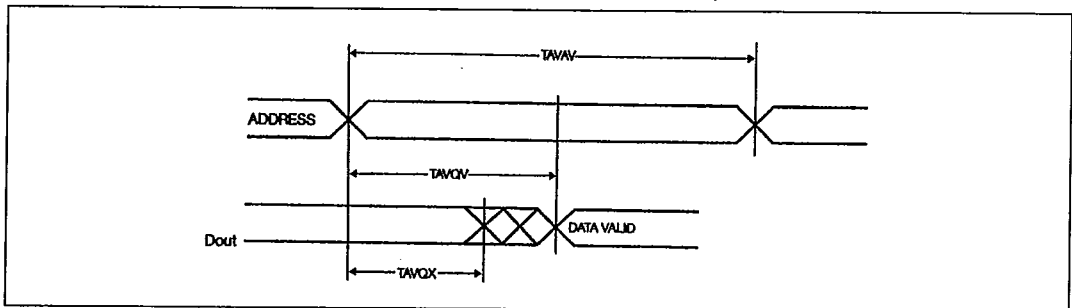
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SYMBOL	PARAMETER	65687 B-5	65687 S-5	65687 -5	65687 C-5	UNIT	VALUE
TAVAV	Read cycle time	35	35	45	45	ns	min
TAVQV	Address access time	35	35	45	45	ns	max
TAVQX	Address Valid to low Z	3	3	3	3	ns	min
TELQV	Chip-select access time	35	35	45	45	ns	max
TELQX	$\overline{CS}$ low to low Z	5	5	5	5	ns	min
TEHQZ	$\overline{CS}$ high to high Z	35	35	45	45	ns	max

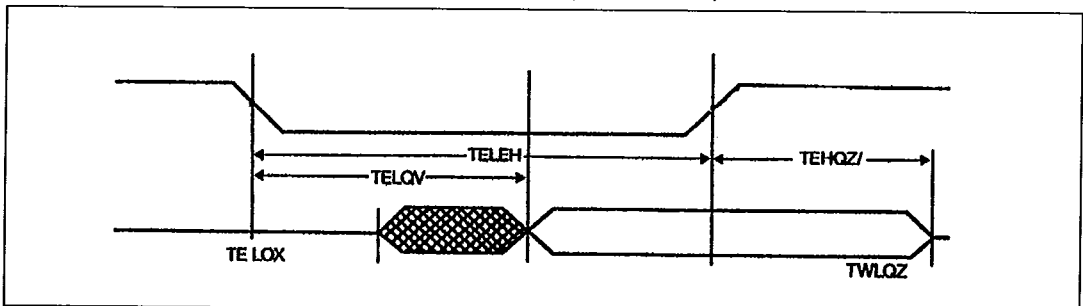
READ CYCLE : Industrial and military specification

SYMBOL	PARAMETER	65687 B-9/2	65687 S-9/2	65687 -9/2	65687 C-9/2	UNIT	VALUE
TAVAV	Read cycle time	45	45	55	55	ns	min
TAVQV	Address access time	45	45	55	55	ns	max
TAVQX	Address Valid to low Z	3	3	3	3	ns	min
TELQV	Chip-select access time	45	45	55	55	ns	max
TELQX	$\overline{CS}$ low to low Z	5	5	5	5	ns	max
TEHQZ	$\overline{CS}$ high to high Z	45	45	55	55	ns	max

READ CYCLE nb 1 (notes 13, 14)



READ CYCLE nb 2 (notes 13, 15)

Notes : 13. $\overline{W}$ is high for read cycle.14. Device is continuously selected, $\overline{CS} = V_{IL}$.15. Address valid prior to or coincident with $\overline{CS}$ transitive.

ORDERING INFORMATION

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Package	Device Type	Grade	Level
HM1	65687	B	-5
0 - Chip form 1 - Ceramic 22 pins 3 - Plastic 22 pins - 300 mils 4* - LCC 22 pins T* - SOIC 24 pins U* - SOJ 24 pins	64 k x 1 Ultimate CMOS static RAM	B - high speed/low current S : high speed/standard current Blank : standard speed/low current C : standard	-5 : Commercial -9 : Industrial -2 : Military -8 : Military with B.I. (B.I. = Burn-in)

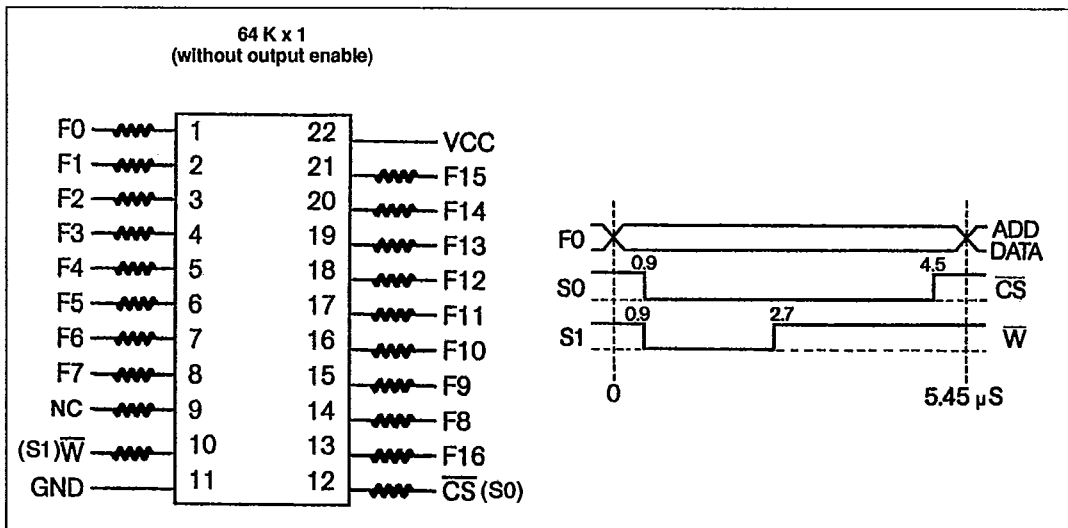
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PACKAGE OUTLINE

For the packaging information, refer to chapter 10

Package reference : Plastic DIL, 300 mils, 22 pins
 Ceramic DIL, 300 mils, 22 pins
 SOIC DIL, 300 mils, 24 pins
 LCC rectangular, 22 pins

BURN-IN SCHEMATICS



VCC = 5 V (-0, +0.5)

R = 1 KΩ per pin

F0 = 91.6 KHz ± 20 %

Fn = 1/2 F n-1

S0 & S1 : programmable signals for
 write / read cycles

NC = Non connected.